

IN THE CLAIMS:

Please add new claim 26 and amend the claims as follows:

1. (Currently Amended) A charged particle beam device ~~[[to]]~~ for inspecting or structure structuring a specimen, comprising:

a) a charged particle beam source configured to generate a charged particle beam;

b) a beam optical system configured to direct the charged particle beam onto ~~said~~ the specimen; and

c) a gas supply system configured to provide ~~providing~~ a gas for the charged particle beam device~~[[;]]~~, wherein the gas supply system ~~comprising~~ comprises a plurality of at least ten tubes to direct ~~said~~ the gas towards a desired region for interaction with the specimen.

2. (Currently Amended) The charged particle beam device according to claim 1, wherein the length, L, of each tube is larger than the square root of the inner cross section area, A, of the tube by more than about 5 times, ~~preferably by more than 50 times and even more preferred by more than 500 times.~~

3. (Currently Amended) The charged particle beam device according to claim 1, wherein the gas supply system comprises a plurality of more than about 100~~[[,]]~~ ~~preferably more than 1000 and even more preferred more than 10,000~~ tubes to direct ~~said~~ the gas.

4. (Currently Amended) The charged particle beam device according to claim 1, wherein the desired region is disposed between the specimen and a circular lower end portion of the beam optical system and comprises a ~~the volume taken by the~~

~~charged particle beam and/or the~~ region where the charged particle beam impinges onto the specimen.

5. (Currently Amended) The charged particle beam device according to claim 1, wherein the charged particle beam device provides a vacuum with a pressure lower than about 1×10^{-3} mbar ~~and preferably lower than 1×10^{-4} mbar.~~

6. (Currently Amended) The charged particle beam device according to claim 1, wherein the inner cross section area, A, of each tube varies along the tube length, L, by less than a factor of about 4, ~~preferably by less than 20% and even more preferred by less than 10%~~ compared to the cross section area, A, at the outlet of the tube.

7. (Currently Amended) The charged particle beam device according to claim 1, wherein the inner cross section area, A, at the outlet of each tube of the plurality of tubes is smaller than about $50,000 \mu\text{m}^2$, ~~preferably smaller than $1000 \mu\text{m}^2$ and even more preferred smaller than $10 \mu\text{m}^2$.~~

8. (Currently Amended) The charged particle beam device according to claim 1, wherein the inlets of the tubes are positioned within a dispensing pressure chamber ~~and preferably within a common dispensing pressure chamber.~~

9. (Previously Presented) The charged particle beam device according to claim 1, wherein the at least ten tubes are oriented essentially in parallel to each other.

10. (Currently Amended) The charged particle beam device according to claim 1, wherein ~~[[,]]~~ the tubes of the plurality of tubes are arranged as a bundle of tubes.

11. (Previously Presented) The charged particle beam device according to claim 10, wherein the bundle of tubes form a tube plate with the tubes reaching from the front side of the tube plate to the reverse side of the tube plate.

12. (Currently Amended) The charged particle beam device according to claim 11, wherein the density of tube outlets on the reverse side of the tube plate is within the range of about 10^2 1/cm² to about 10^7 1/cm² ~~and preferably within the range of 10^4 1/cm² to 10^6 1/cm².~~

13. (Currently Amended) The charged particle beam device according to claim 1, wherein the length of each tube is larger than the diameter of the inner cross section, A, of each tube of the plurality of tubes is by at least a factor of about 10 ~~characterized by a characteristic diameter, D.~~

14. (Currently Amended) The charged particle beam device according to claim 13, wherein during normal operation, the free path length of the gas at the outlet of each tube is larger than 1/10 of the length of the tube, L, ~~preferably larger than one time the length of the tube, L, and even more preferred larger than ten times the length of the tube, L.~~

15. (Currently Amended) The charged particle beam device according to claim 1, wherein during normal operation, the peaking-ratio of the gas at the outlet of each tube of the plurality of tubes is larger than two, ~~preferably larger than five and even more preferred larger than 20.~~

16. (Currently Amended) The charged particle beam device according to claim 1, wherein during normal operation, the pressure at the inlet of each tube is smaller than

10 mbar, ~~preferably smaller than 1 mbar and even more preferred smaller than 0.1 mbar.~~

17. (Previously Presented) The charged particle beam device according to claim 1, wherein the beam optical system comprises a final focus lens to focus the charged particle beam onto the specimen.

18. (Previously Presented) The charged particle beam device according to claim 17, wherein during normal operation, the plurality of tubes directs the gas into the charged particle beam in the region between the final focus lens and the surface of the specimen.

19. (Currently Amended) The charged particle beam device according to claim 17, wherein the tubes of the plurality of tubes are arranged at an angle, α , smaller than 60 degrees, ~~preferably smaller than 40 degrees, and even more preferred smaller than 20 degrees~~ with respect to the optical axis of the final focus lens to direct the gas towards the specimen.

20. (Currently Amended) The charged particle beam device according to claim 17, wherein the beam optical system comprises a reference electrode to generate an electric field to accelerate ~~the~~ an ionized gas towards the specimen.

21. (Currently Amended) The charged particle beam device according to claim 11, wherein the plurality of tubes comprises at least two tube plates ~~and preferably at least eight tube plates.~~

22. (Currently Amended) The charged particle beam device according to claim 21, wherein the at least two tube plates are arranged ~~as~~ in a semicircle around the

optical axis of ~~the~~ a final focus lens configured to focus the charged particle beam onto the specimen.

23. (Previously Presented) The charged particle beam device according to claim 21, wherein the gas is a neutral gas when passing through the tubes.

24. (Currently Amended) The charged particle beam device according to claim 23, wherein the neutral gas is at least one of ~~a neutral gas like~~ N₂ ~~or,~~ an inert gas like ~~He, Ne, Ar, Kr, Xe, or CH₄~~ or a mixture of the above mentioned gases.

25. (Previously Presented) The charged particle beam device according to claim 21, wherein the at least ten tubes are positioned in the vicinity of the specimen.

26. (New) The charged particle beam device according to claim 24, wherein the inert gas comprises at least one of He, Ne, Ar, Kr, Xe and CH₄.